

In The Claims:

The listing of claims will replace all prior versions, and listings, of claims in the application.

Listing of Claims:

1. (currently amended) A method for fabricating a semiconductor device, the method comprising:
forming a first conductive layer for a first electrode on a semiconductor substrate;
forming a dielectric layer on the first conductive layer;
forming a second conductive layer for a second electrode on the dielectric layer;
after forming the dielectric layer and after forming the second conductive layer,
removing portions of the second conductive layer and portions of the dielectric layer thereby exposing portions of the first conductive layer previously covered by the dielectric layer; and
performing a thermal process on the second conductive layer and the dielectric layer at a temperature of at least about 400°C.
2. (withdrawn) The method of claim 1, wherein the thermal process comprises:
heating the second conductive layer and the dielectric layer to a first temperature in the range of about 450°C to 600°C in an inert gas atmosphere; and
then, heating the second conductive layer and the dielectric layer to a second temperature in the range of about 350°C to 450°C in a gas atmosphere including oxygen.
3. (original) The method of claim 1, wherein forming the dielectric layer is preceded by:
depositing a seed layer on the first conductive layer; and
crystallizing the seed layer.
4. (original) The method of claim 1, wherein the performing the thermal process comprises heating the dielectric layer and the second conductive layer at a temperature in the range of about 450°C to 600°C in an inert gas atmosphere.

5. (withdrawn) The method of claim 1, wherein performing the thermal process comprises:

heating the dielectric layer and the second conductive layer at a first temperature in the range of about 350°C to 450°C in a gas atmosphere including oxygen; and

then, heating the dielectric layer and the second conductive layer at a second temperature in the range of about 450°C to 600°C in an inert gas atmosphere.

6. (withdrawn) The method of claim 1, wherein performing the thermal process comprises:

heating the dielectric layer and the second conductive layer at a first temperature in the range of about 650°C to 700°C in an inert gas atmosphere; and

then, heating the dielectric layer and the second conductive layer at a second temperature in the range of about 350°C to 450°C in a gas atmosphere including oxygen.

7. (withdrawn) The method of claim 1, wherein performing the thermal process comprises heating the dielectric layer and the second conductive layer at a temperature in the range of about 650°C to 700°C in an inert gas atmosphere.

8. (withdrawn) The method of claim 1, wherein performing the thermal process comprises:

heating the dielectric layer and the second conductive layer at a first temperature in the range of about 350°C to 450°C in a gas atmosphere including oxygen; and

then, heating the dielectric layer and the second conductive layer at a second temperature in the range of about 650°C to 700°C in an inert gas atmosphere.

9. (original) The method of claim 1, wherein the first conductive layer comprises at least one material selected from the group consisting of platinum (Pt), ruthenium (Ru), iridium (Ir), rhodium (Rh), and/or osmium (Os).

10. (original) The method of claim 9, wherein the second conductive layer comprises a same material as the first conductive layer.

11. (original) The method of claim 1, wherein forming the dielectric layer comprises forming a tantalum oxide layer.

12. (original) The method of claim 1, wherein forming the dielectric layer comprises depositing tantalum oxide at a temperature in the range of about 380°C to 500°C using chemical vapor deposition (CVD).

13. (original) The method of claim 1, wherein removing portions of the second conductive layer and the dielectric layer comprises dry etching the second conductive layer and the dielectric layer.

14. (original) The method of claim 1 wherein performing the thermal process comprises performing the thermal process on the second conductive layer and the dielectric layer after removing portions of the second conductive layer and the dielectric layer.

15. (currently amended) A method for fabricating a semiconductor device, the method comprising:

forming a first conductive layer for a first electrode on a semiconductor substrate;
forming a tantalum oxide layer on the first conductive layer;
forming a second conductive layer for a second electrode on the tantalum oxide layer;
after forming the tantalum oxide layer and after forming the second conductive layer,
removing portions of the second conductive layer and portions of the tantalum oxide layer
thereby exposing portions of the first conductive layer previously covered by the tantalum oxide
layer; and
performing a thermal process to reduce an interface stress between the second conductive layer and the tantalum oxide layer and to cure the tantalum oxide layer, while maintaining the tantalum oxide layer in a substantially amorphous state during and after the thermal process.

16. (withdrawn) The method of claim 15, wherein performing the thermal process comprises:

heating the tantalum oxide layer and the second conductive layer at a first temperature in the range of about 450°C to 600°C in an inert gas atmosphere; and

then, heating the tantalum oxide layer and the second conductive layer at a second temperature in the range of about 350°C to 450°C in a gas atmosphere including oxygen.

17. (withdrawn) The method of claim 16, wherein heating at the first temperature and heating at the second temperature are performed *in situ*.

18. (original) The method of claim 15, wherein performing the thermal process comprises heating the tantalum oxide layer and the second conductive layer at a temperature in the range of about 450°C to 600°C in an inert gas atmosphere.

19. (withdrawn) The method of claim 15, wherein the thermal process comprises:
heating the tantalum oxide layer and the second conductive layer at a first temperature in the range of about 350°C to 450°C in a gas atmosphere including oxygen; and
then, heating the tantalum oxide layer and the second conductive layer at a second temperature in the range of about 450°C to 600°C in an inert gas atmosphere.

20. (withdrawn) The method of claim 15, wherein heating at the first temperature and heating at the second temperature are performed *in situ*.

21. (original) The method of claim 15, wherein the first conductive layer comprises at least one material selected from the group consisting of Pt, Ru, Ir, Rh, and/or Os.

22. (original) The method of claim 21, wherein the second conductive layer comprises a same material as the first conductive layer.

23. (original) The method of claim 15, wherein forming the tantalum oxide layer comprises depositing tantalum oxide at a temperature in the range of about 380°C to 500°C using chemical vapor deposition.

Claims 24-32 (canceled).

33. (currently amended) A method for fabricating a semiconductor device, the method comprising:

forming a first conductive layer for a first electrode on a semiconductor substrate;
forming a seed layer on the first conductive layer;
crystallizing the seed layer;
forming a tantalum oxide layer on the crystallized seed layer;
forming a second conductive layer for a second electrode on the tantalum oxide layer;
after forming the tantalum oxide layer and after forming the second conductive layer,
removing portions of the second conductive layer and portions of the tantalum oxide layer
thereby exposing portions of the first conductive layer previously covered by the tantalum oxide
layer; and
performing a thermal process to reduce an interface stress between the second conductive layer and the tantalum oxide layer and to cure the tantalum oxide layer.

34. (withdrawn) The method of claim 33, wherein performing the thermal process comprises:

heating the second conductive layer and the tantalum oxide layer at a first temperature in the range of about 450°C to 600°C in an inert gas atmosphere; and
then, heating the second conductive layer and the tantalum oxide layer at a second temperature in the range of about 350°C to 450°C in a gas atmosphere including oxygen.

35. (withdrawn) The method of claim 34, wherein heating at the first temperature and heating at the second temperature are performed *in situ*.

36. (original) The method of claim 33, wherein forming the seed layer comprises forming a seed layer having a thickness in the range of about 30Å to 60Å.

37. (original) The method of claim 36, wherein crystallizing the seed layer comprises heating the seed layer at a temperature in the range of 650°C to 750°C.

38. (original) The method of claim 33, wherein the first conductive layer comprises at least one material selected from the group consisting of Pt, Ru, Ir, Rh, and/or Os.

39. (original) The method of claim 38, wherein the second conductive layer comprise a same material as the first conductive layer.

40. (original) The method of claim 33, wherein forming the tantalum oxide layer comprises depositing tantalum oxide at a temperature in the range of 380°C to 500°C using chemical vapor deposition.

41. (original) The method of Claim 33 wherein forming the seed layer comprises forming a seed layer of a tantalum oxide layer.

42. (new) The method of Claim 1 wherein performing a thermal process comprises performing a thermal process after removing portions of the second conductive layer and after removing portions of the dielectric layer.

43. (new) The method of Claim 15 wherein performing a thermal process comprises performing a thermal process after removing portions of the second conductive layer and after removing portions of the tantalum oxide layer.

44. (new) The method of Claim 33 wherein performing a thermal process comprises performing a thermal process after removing portions of the second conductive layer and after removing portions of the tantalum oxide layer.